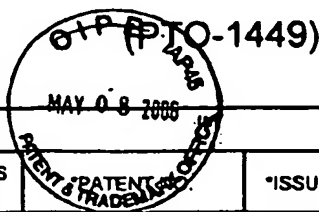


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Young Dae KIM

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2879

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